

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S16	6664	"269".clas. and groove	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/03/19 14:12
S17	288	S16 and test	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/03/19 14:13
S18	26	("20010015795"   "20020075469"   "20020196421"   "20030030402"   "20040012768"   "20040051402"   "20040051854"   "20040201834"   "4924258"   "5022619"   "5537186"   "5744924"   "5969441"   "6002465"   "6260282"   "6271640"   "6327022"   "6498350"   "6550133"   "6594887"   "6603531"   "6639654"   "6665054"   "6703259"   "6721041"   "6724466").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2008/03/19 14:16
S19	6	("5008615"   "5440231"   "5897290"   "5975835"   "6045318"   "6507185").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2008/03/19 14:22
S20	10393	"414".clas. and groove	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/03/19 14:32

S21	1416	S20 and (test\$4 or inspect\$)	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/03/19 14:33
S22	32	S21 and (leadframe or lead near5 frame)	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/03/19 14:33
S23	36	S21 and "324".clas.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/03/19 14:36
S24	86	(groove or trench or rail) near5 semiconductor and 324/754-770.ccls.	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/03/19 14:39
S25	147	carrier near5 groove near5 semiconductor	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/03/19 14:47
S26	15	("3231797"   "3254274"   "3271507"   "3274459"   "3404214"   "3590341"   "3740672"   "3748544"   "3828228"   "3886505").PN.	US_PGPUB; USPAT; USOCR	OR	ON	2008/03/19 15:10
S27	314	carrier near5 (groove or trench or rail or depression) near5 semiconductor	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/03/19 15:11
S28	314	S27 not S26	US_PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/03/19 15:12

S29	2987	(groove or trench or rail or depression) near5 semiconductor and test	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/03/19 15:16
S30	11	S29 and "414".clas.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/03/19 15:16
S31	1958	S29 and "257".clas.	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/03/19 15:18
S32	473	S31 and \$4frame	US-PGPUB; USPAT; USOCR; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2008/03/19 15:19

3/24/2008 3:45:27 PM

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